


<b>Search Notes</b>  	<b>Application/Control No.</b>  10812051	<b>Applicant(s)/Patent Under Reexamination</b>  MIWA ET AL.
	<b>Examiner</b>  Hung, Yubin	<b>Art Unit</b>  2624

SEARCHED			
Class	Subclass	Date	Examiner
382	164, 167, 173, 199, 274	10/05/07	YH
345	593	10/05/07	YH
358	520	10/05/07	YH

SEARCH NOTES			
Search Notes		Date	Examiner
EAST T (USPGPUB, USPAT, EPO, JPO, DERWENT, IBM-TDB)		10/18/07	YH
IEEE Xplore		10/18/07	YH

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner